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### Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

### Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

#### Details

Product Status	Obsolete
Core Processor	PowerPC e600
Number of Cores/Bus Width	2 Core, 32-Bit
Speed	1.0GHz
Co-Processors/DSP	-
RAM Controllers	DDR, DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	-40°C ~ 105°C (TA)
Security Features	-
Package / Case	1023-BBGA, FCBGA
Supplier Device Package	1023-FCCBGA (33x33)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/nxp-semiconductors/mc8641dthx1000gc">https://www.e-xfl.com/product-detail/nxp-semiconductors/mc8641dthx1000gc</a>

## 2 Electrical Characteristics

This section provides the AC and DC electrical specifications and thermal characteristics for the MPC8641. The MPC8641 is currently targeted to these specifications.

### 2.1 Overall DC Electrical Characteristics

This section covers the ratings, conditions, and other characteristics.

#### 2.1.1 Absolute Maximum Ratings

Table 1 provides the absolute maximum ratings.

**Table 1. Absolute Maximum Ratings<sup>1</sup>**

Characteristic	Symbol	Absolute Maximum Value	Unit	Notes
Cores supply voltages	$V_{DD\_Core0}$ , $V_{DD\_Core1}$	-0.3 to 1.21 V	V	2
Cores PLL supply	$AV_{DD\_Core0}$ , $AV_{DD\_Core1}$	-0.3 to 1.21 V	V	—
SerDes Transceiver Supply (Ports 1 and 2)	$SV_{DD}$	-0.3 to 1.21 V	V	—
SerDes Serial I/O Supply Port 1	$XV_{DD\_SRDS1}$	-0.3 to 1.21V	V	—
SerDes Serial I/O Supply Port 2	$XV_{DD\_SRDS2}$	-0.3 to 1.21 V	V	—
SerDes DLL and PLL supply voltage for Port 1 and Port 2	$AV_{DD\_SRDS1}$ , $AV_{DD\_SRDS2}$	-0.3 to 1.21V	V	—
Platform Supply voltage	$V_{DD\_PLAT}$	-0.3 to 1.21V	V	—
Local Bus and Platform PLL supply voltage	$AV_{DD\_LB}$ , $AV_{DD\_PLAT}$	-0.3 to 1.21V	V	—
DDR and DDR2 SDRAM I/O supply voltages	$D1\_GV_{DD}$ , $D2\_GV_{DD}$	-0.3 to 2.75 V	V	3
		-0.3 to 1.98 V	V	3
eTSEC 1 and 2 I/O supply voltage	$LV_{DD}$	-0.3 to 3.63 V	V	4
		-0.3 to 2.75 V	V	4
eTSEC 3 and 4 I/O supply voltage	$TV_{DD}$	-0.3 to 3.63 V	V	4
		-0.3 to 2.75 V	V	4
Local Bus, DUART, DMA, Multiprocessor Interrupts, System Control & Clocking, Debug, Test, Power management, I <sup>2</sup> C, JTAG and Miscellaneous I/O voltage	$OV_{DD}$	-0.3 to 3.63 V	V	—

**Table 24. GMII, MII, RMII, TBI and FIFO DC Electrical Characteristics (continued)**

Parameter	Symbol	Min	Max	Unit	Notes
Input low current ( $V_{IN} = \text{GND}$ )	$I_{IL}$	-600	—	$\mu\text{A}$	3

**Notes:**

- <sup>1</sup>  $LV_{DD}$  supports eTSECs 1 and 2.
- <sup>2</sup>  $TV_{DD}$  supports eTSECs 3 and 4.
- <sup>3</sup> The symbol  $V_{IN}$ , in this case, represents the  $LV_{IN}$  and  $TV_{IN}$  symbols referenced in [Table 1](#) and [Table 2](#).

**Table 25. GMII, RGMII, RTBI, TBI and FIFO DC Electrical Characteristics**

Parameters	Symbol	Min	Max	Unit	Notes
Supply voltage 2.5 V	$LV_{DD}/TV_{DD}$	2.375	2.625	V	1,2
Output high voltage ( $LV_{DD}/TV_{DD} = \text{Min}$ , $I_{OH} = -1.0 \text{ mA}$ )	$V_{OH}$	2.00	—	V	—
Output low voltage ( $LV_{DD}/TV_{DD} = \text{Min}$ , $I_{OL} = 1.0 \text{ mA}$ )	$V_{OL}$	—	0.40	V	—
Input high voltage	$V_{IH}$	1.70	—	V	—
Input low voltage	$V_{IL}$	—	0.90	V	—
Input high current ( $V_{IN} = LV_{DD}$ , $V_{IN} = TV_{DD}$ )	$I_{IH}$	—	10	$\mu\text{A}$	1, 2,3
Input low current ( $V_{IN} = \text{GND}$ )	$I_{IL}$	-15	—	$\mu\text{A}$	3

**Note:**

- <sup>1</sup>  $LV_{DD}$  supports eTSECs 1 and 2.
- <sup>2</sup>  $TV_{DD}$  supports eTSECs 3 and 4.
- <sup>3</sup> Note that the symbol  $V_{IN}$ , in this case, represents the  $LV_{IN}$  and  $TV_{IN}$  symbols referenced in [Table 1](#) and [Table 2](#).

## 8.2 FIFO, GMII, MII, TBI, RGMII, RMII, and RTBI AC Timing Specifications

The AC timing specifications for FIFO, GMII, MII, TBI, RGMII, RMII and RTBI are presented in this section.

### 8.2.1 FIFO AC Specifications

The basis for the AC specifications for the eTSEC's FIFO modes is the double data rate RGMII and RTBI specifications, since they have similar performance and are described in a source-synchronous fashion like FIFO modes. However, the FIFO interface provides deliberate skew between the transmitted data and source clock in GMII fashion.

When the eTSEC is configured for FIFO modes, all clocks are supplied from external sources to the relevant eTSEC interface. That is, the transmit clock must be applied to the eTSEC $n$ 's TSEC $n$ \_TX\_CLK, while the receive clock must be applied to pin TSEC $n$ \_RX\_CLK. The eTSEC internally uses the transmit

## 8.2.4 TBI AC Timing Specifications

This section describes the TBI transmit and receive AC timing specifications.

### 8.2.4.1 TBI Transmit AC Timing Specifications

Table 32 provides the TBI transmit AC timing specifications.

**Table 32. TBI Transmit AC Timing Specifications**

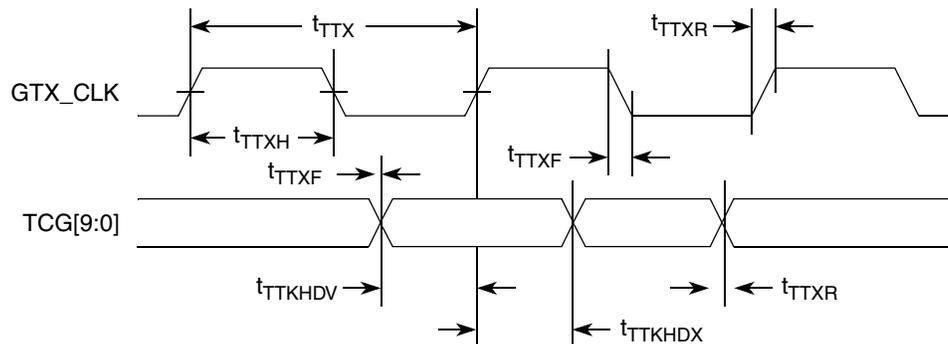
At recommended operating conditions with  $L/TV_{DD}$  of  $3.3\text{ V} \pm 5\%$  and  $2.5\text{ V} \pm 5\%$ .

Parameter/Condition	Symbol <sup>1</sup>	Min	Typ	Max	Unit
TCG[9:0] setup time GTX_CLK going high	$t_{\text{TTKHdV}}$	2.0	—	—	ns
TCG[9:0] hold time from GTX_CLK going high	$t_{\text{TTKHdX}}$	1.0	—	—	ns
GTX_CLK rise time (20%–80%)	$t_{\text{TTXr}}^2$	—	—	1.0	ns
GTX_CLK fall time (80%–20%)	$t_{\text{TTXf}}^2$	—	—	1.0	ns

**Notes:**

- The symbols used for timing specifications herein follow the pattern of  $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$  for inputs and  $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$  for outputs. For example,  $t_{\text{TTKHdV}}$  symbolizes the TBI transmit timing (TT) with respect to the time from  $t_{\text{TTX}}$  (K) going high (H) until the referenced data signals (D) reach the valid state (V) or setup time. Also,  $t_{\text{TTKHdX}}$  symbolizes the TBI transmit timing (TT) with respect to the time from  $t_{\text{TTX}}$  (K) going high (H) until the referenced data signals (D) reach the invalid state (X) or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of  $t_{\text{TTX}}$  represents the TBI (T) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
- Guaranteed by design.

Figure 16 shows the TBI transmit AC timing diagram.



**Figure 16. TBI Transmit AC Timing Diagram**

## 8.2.7 RMII AC Timing Specifications

This section describes the RMII transmit and receive AC timing specifications.

### 8.2.7.1 RMII Transmit AC Timing Specifications

The RMII transmit AC timing specifications are in [Table 36](#).

**Table 36. RMII Transmit AC Timing Specifications**

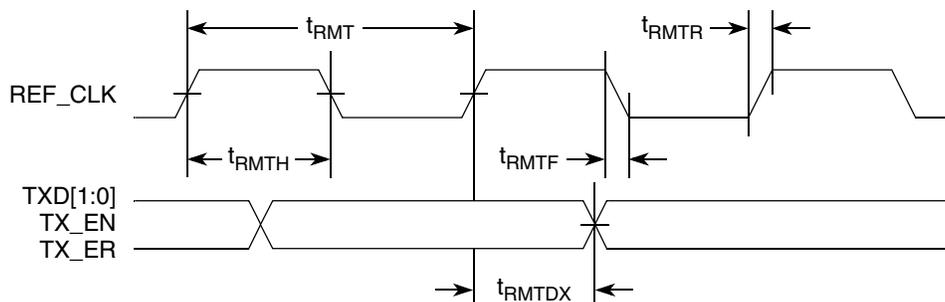
At recommended operating conditions with  $L/TV_{DD}$  of  $3.3\text{ V} \pm 5\%$ .

Parameter/Condition	Symbol <sup>1</sup>	Min	Typ	Max	Unit
REF_CLK clock period	$t_{RMT}$	—	20.0	—	ns
REF_CLK duty cycle	$t_{RMTH}/t_{RMT}$	35	50	65	%
REF_CLK peak-to-peak jitter	$t_{RMTJ}$	—	—	250	ps
Rise time REF_CLK (20%–80%)	$t_{RMTR}$	1.0	—	2.0	ns
Fall time REF_CLK (80%–20%)	$t_{RMTF}$	1.0	—	2.0	ns
REF_CLK to RMII data TXD[1:0], TX_EN delay	$t_{RMTDX}$	1.0	—	10.0	ns

**Note:**

- The symbols used for timing specifications herein follow the pattern of  $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$  for inputs and  $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$  for outputs. For example,  $t_{MTKHDX}$  symbolizes MII transmit timing (MT) for the time  $t_{MTX}$  clock reference (K) going high (H) until data outputs (D) are invalid (X). Note that, in general, the clock reference symbol representation is based on two to three letters representing the clock of a particular functional. For example, the subscript of  $t_{MTX}$  represents the MII(M) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

[Figure 20](#) shows the RMII transmit AC timing diagram.



**Figure 20. RMII Transmit AC Timing Diagram**

## 9 Ethernet Management Interface Electrical Characteristics

The electrical characteristics specified here apply to MII management interface signals MDIO (management data input/output) and MDC (management data clock). The electrical characteristics for GMII, RGMII, RMII, TBI and RTBI are specified in “[Section 8, “Ethernet: Enhanced Three-Speed Ethernet \(eTSEC\), MII Management.”](#)”

### 9.1 MII Management DC Electrical Characteristics

The MDC and MDIO are defined to operate at a supply voltage of 3.3 V. The DC electrical characteristics for MDIO and MDC are provided in [Table 38](#).

**Table 38. MII Management DC Electrical Characteristics**

Parameter	Symbol	Min	Max	Unit
Supply voltage (3.3 V)	$OV_{DD}$	3.135	3.465	V
Output high voltage ( $OV_{DD} = \text{Min}$ , $I_{OH} = -1.0 \text{ mA}$ )	$V_{OH}$	2.10	—	V
Output low voltage ( $OV_{DD} = \text{Min}$ , $I_{OL} = 1.0 \text{ mA}$ )	$V_{OL}$	—	0.50	V
Input high voltage	$V_{IH}$	1.70	—	V
Input low voltage	$V_{IL}$	—	0.90	V
Input high current ( $OV_{DD} = \text{Max}$ , $V_{IN}^1 = 2.1 \text{ V}$ )	$I_{IH}$	—	40	$\mu\text{A}$
Input low current ( $OV_{DD} = \text{Max}$ , $V_{IN} = 0.5 \text{ V}$ )	$I_{IL}$	-600	—	$\mu\text{A}$

**Note:**

1. Note that the symbol  $V_{IN}$ , in this case, represents the  $OV_{IN}$  symbol referenced in [Table 1](#) and [Table 2](#).

### 9.2 MII Management AC Electrical Specifications

[Table 39](#) provides the MII management AC timing specifications.

**Table 39. MII Management AC Timing Specifications**

At recommended operating conditions with  $OV_{DD}$  is 3.3 V  $\pm$  5%.

Parameter/Condition	Symbol <sup>1</sup>	Min	Typ	Max	Unit	Notes
MDC frequency	$f_{MDC}$	2.5	—	9.3	MHz	2, 4
MDC period	$t_{MDC}$	80	—	400	ns	—
MDC clock pulse width high	$t_{MDCH}$	32	—	—	ns	—
MDC to MDIO valid	$t_{MDKHdV}$	$16 \cdot t_{MPXCLK}$	—	—	ns	5
MDC to MDIO delay	$t_{MDKHdX}$	10	—	$16 \cdot t_{MPXCLK}$	ns	3, 5
MDIO to MDC setup time	$t_{MDdVKH}$	5	—	—	ns	—

To illustrate these definitions using real values, consider the case of a CML (Current Mode Logic) transmitter that has a common mode voltage of 2.25 V and each of its outputs, TD and  $\overline{\text{TD}}$ , has a swing that goes between 2.5 V and 2.0 V. Using these values, the peak-to-peak voltage swing of each signal (TD or  $\overline{\text{TD}}$ ) is 500 mV p-p, which is referred as the single-ended swing for each signal. In this example, since the differential signaling environment is fully symmetrical, the transmitter output's differential swing ( $V_{\text{OD}}$ ) has the same amplitude as each signal's single-ended swing. The differential output signal ranges between 500 mV and -500 mV, in other words,  $V_{\text{OD}}$  is 500 mV in one phase and -500 mV in the other phase. The peak differential voltage ( $V_{\text{DIFFp}}$ ) is 500 mV. The peak-to-peak differential voltage ( $V_{\text{DIFFp-p}}$ ) is 1000 mV p-p.

## 13.2 SerDes Reference Clocks

The SerDes reference clock inputs are applied to an internal PLL whose output creates the clock used by the corresponding SerDes lanes. The SerDes reference clocks inputs are  $\text{SD}n\_REF\_CLK$  and  $\overline{\text{SD}n\_REF\_CLK}$  for PCI Express and Serial RapidIO.

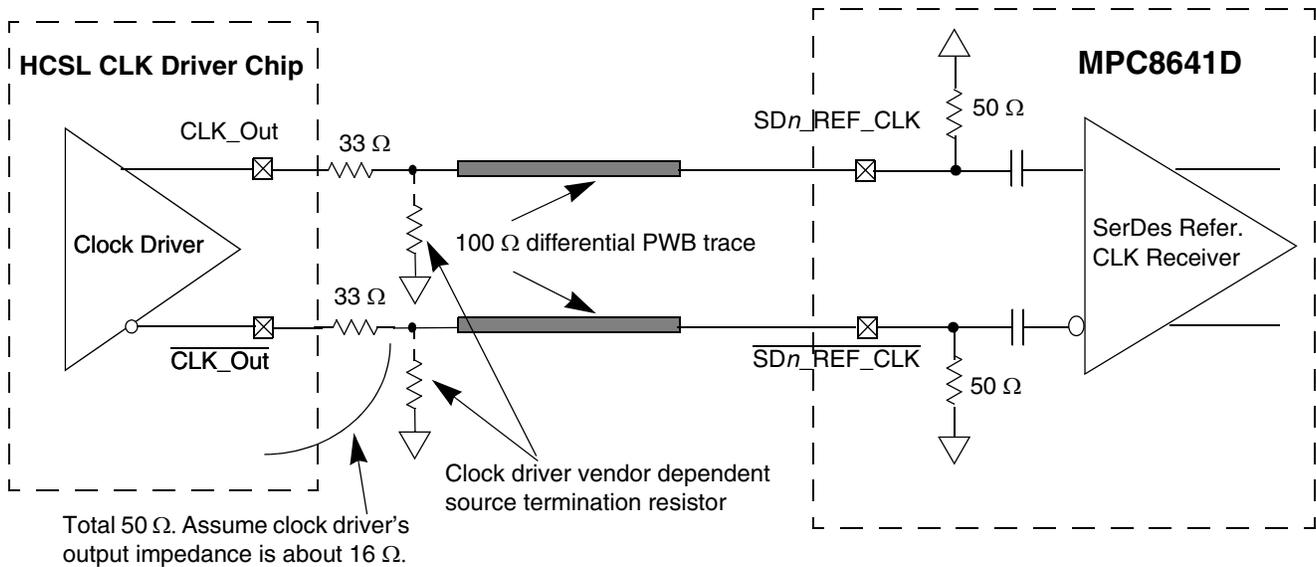
The following sections describe the SerDes reference clock requirements and some application information.

### 13.2.1 SerDes Reference Clock Receiver Characteristics

Figure 39 shows a receiver reference diagram of the SerDes reference clocks.

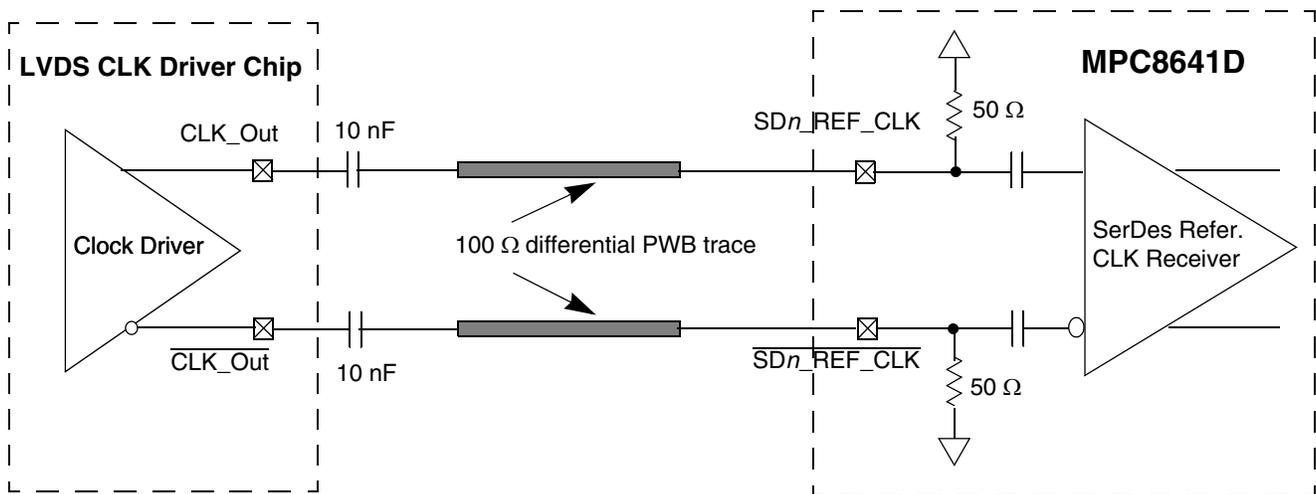
- The supply voltage requirements for  $XV_{\text{DD\_SRDS}n}$  are specified in Table 1 and Table 2.
- SerDes Reference Clock Receiver Reference Circuit Structure
  - The  $\text{SD}n\_REF\_CLK$  and  $\overline{\text{SD}n\_REF\_CLK}$  are internally AC-coupled differential inputs as shown in Figure 39. Each differential clock input ( $\text{SD}n\_REF\_CLK$  or  $\overline{\text{SD}n\_REF\_CLK}$ ) has a 50- $\Omega$  termination to SGND followed by on-chip AC-coupling.
  - The external reference clock driver must be able to drive this termination.
  - The SerDes reference clock input can be either differential or single-ended. Refer to the Differential Mode and Single-ended Mode description below for further detailed requirements.
- The maximum average current requirement that also determines the common mode voltage range
  - When the SerDes reference clock differential inputs are DC coupled externally with the clock driver chip, the maximum average current allowed for each input pin is 8 mA. In this case, the exact common mode input voltage is not critical as long as it is within the range allowed by the maximum average current of 8 mA (refer to the following bullet for more detail), since the input is AC-coupled on-chip.
  - This current limitation sets the maximum common mode input voltage to be less than 0.4 V ( $0.4 \text{ V}/50 = 8 \text{ mA}$ ) while the minimum common mode input level is 0.1 V above SGND. For example, a clock with a 50/50 duty cycle can be produced by a clock driver with output driven by its current source from 0 mA to 16 mA (0–0.8 V), such that each phase of the differential input has a single-ended swing from 0 V to 800 mV with the common mode voltage at 400 mV.
  - If the device driving the  $\text{SD}n\_REF\_CLK$  and  $\overline{\text{SD}n\_REF\_CLK}$  inputs cannot drive 50  $\Omega$  to SGND DC, or it exceeds the maximum input current limitations, then it must be AC-coupled off-chip.

Figure 43 shows the SerDes reference clock connection reference circuits for HCSL type clock driver. It assumes that the DC levels of the clock driver chip is compatible with MPC8641D SerDes reference clock input's DC requirement.



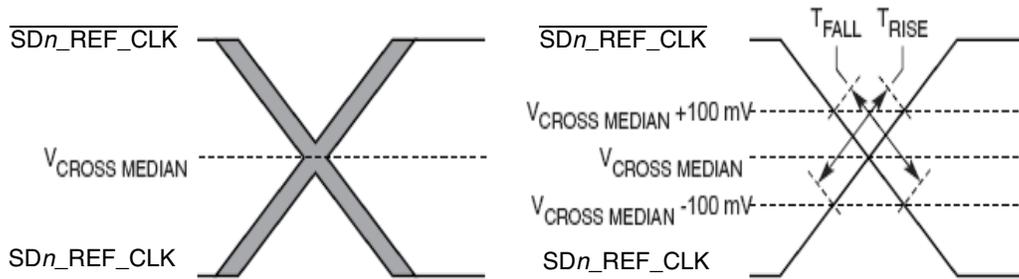
**Figure 43. DC-Coupled Differential Connection with HCSL Clock Driver (Reference Only)**

Figure 44 shows the SerDes reference clock connection reference circuits for LVDS type clock driver. Since LVDS clock driver's common mode voltage is higher than the MPC8641D SerDes reference clock input's allowed range (100 to 400 mV), AC-coupled connection scheme must be used. It assumes the LVDS output driver features 50-Ω termination resistor. It also assumes that the LVDS transmitter establishes its own common mode level without relying on the receiver or other external component.



**Figure 44. AC-Coupled Differential Connection with LVDS Clock Driver (Reference Only)**

Figure 45 shows the SerDes reference clock connection reference circuits for LVPECL type clock driver. Since LVPECL driver's DC levels (both common mode voltages and output swing) are incompatible with



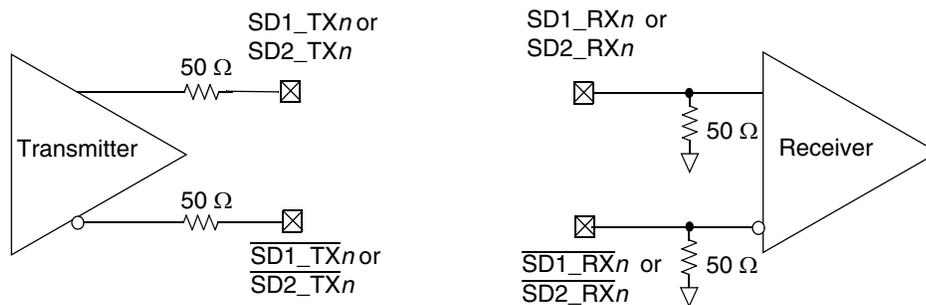
**Figure 48. Single-Ended Measurement Points for Rise and Fall Time Matching**

The other detailed AC requirements of the SerDes Reference Clocks is defined by each interface protocol based on application usage. Refer to the following sections for detailed information:

- [Section 14.2, “AC Requirements for PCI Express SerDes Clocks”](#)
- [Section 15.2, “AC Requirements for Serial RapidIO SDn\\_REF\\_CLK and SDn\\_REF\\_CLK”](#)

### 13.3 SerDes Transmitter and Receiver Reference Circuits

Figure 49 shows the reference circuits for SerDes data lane’s transmitter and receiver.



**Figure 49. SerDes Transmitter and Receiver Reference Circuits**

The DC and AC specification of SerDes data lanes are defined in each interface protocol section below (PCI Express or Serial Rapid IO) in this document based on the application usage:”

- [Section 14, “PCI Express”](#)
- [Section 15, “Serial RapidIO”](#)

Note that external AC Coupling capacitor is required for the above two serial transmission protocols with the capacitor value defined in specification of each protocol section.

## 14 PCI Express

This section describes the DC and AC electrical specifications for the PCI Express bus of the MPC8641.

## 14.1 DC Requirements for PCI Express $SDn\_REF\_CLK$ and $\overline{SDn\_REF\_CLK}$

For more information, see [Section 13.2, “SerDes Reference Clocks.”](#)

## 14.2 AC Requirements for PCI Express SerDes Clocks

[Table 48](#) lists AC requirements.

**Table 48.  $SDn\_REF\_CLK$  and  $\overline{SDn\_REF\_CLK}$  AC Requirements**

Symbol	Parameter Description	Min	Typical	Max	Units	Notes
$t_{REF}$	REFCLK cycle time	—	10	—	ns	—
$t_{REFCJ}$	REFCLK cycle-to-cycle jitter. Difference in the period of any two adjacent REFCLK cycles	—	—	100	ps	—
$t_{REFPJ}$	Phase jitter. Deviation in edge location with respect to mean edge location	-50	—	50	ps	—

## 14.3 Clocking Dependencies

The ports on the two ends of a link must transmit data at a rate that is within 600 parts per million (ppm) of each other at all times. This is specified to allow bit rate clock sources with a +/- 300 ppm tolerance.

## 14.4 Physical Layer Specifications

The following is a summary of the specifications for the physical layer of PCI Express on this device. For further details as well as the specifications of the Transport and Data Link layer please use the PCI EXPRESS Base Specification. REV. 1.0a document.

### 14.4.1 Differential Transmitter (TX) Output

[Table 49](#) defines the specifications for the differential output at all transmitters (TXs). The parameters are specified at the component pins.

**Table 49. Differential Transmitter (TX) Output Specifications**

Symbol	Parameter	Min	Nom	Max	Units	Comments
UI	Unit Interval	399.88	400	400.12	ps	Each UI is 400 ps ± 300 ppm. UI does not account for Spread Spectrum Clock dictated variations. See Note 1.
$V_{TX-DIFFp-p}$	Differential Peak-to-Peak Output Voltage	0.8	—	1.2	V	$V_{TX-DIFFp-p} = 2 *  V_{TX-D+} - V_{TX-D-} $ See Note 2.
$V_{TX-DE-RATIO}$	De-Emphasized Differential Output Voltage (Ratio)	-3.0	-3.5	-4.0	dB	Ratio of the $V_{TX-DIFFp-p}$ of the second and following bits after a transition divided by the $V_{TX-DIFFp-p}$ of the first bit after a transition. See Note 2.

**Table 49. Differential Transmitter (TX) Output Specifications (continued)**

Symbol	Parameter	Min	Nom	Max	Units	Comments
$T_{TX-EYE}$	Minimum TX Eye Width	0.70	—	—	UI	The maximum Transmitter jitter can be derived as $T_{TX-MAX-JITTER} = 1 - T_{TX-EYE} = 0.3$ UI. See Notes 2 and 3.
$T_{TX-EYE-MEDIAN-to-MAX-JITTER}$	Maximum time between the jitter median and maximum deviation from the median.	—	—	0.15	UI	Jitter is defined as the measurement variation of the crossing points ( $V_{TX-DIFFp-p} = 0$ V) in relation to a recovered TX UI. A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. Jitter is measured using all edges of the 250 consecutive UI in the center of the 3500 UI used for calculating the TX UI. See Notes 2 and 3.
$T_{TX-RISE}, T_{TX-FALL}$	D+/D- TX Output Rise/Fall Time	0.125	—	—	UI	See Notes 2 and 5
$V_{TX-CM-ACp}$	RMS AC Peak Common Mode Output Voltage	—	—	20	mV	$V_{TX-CM-ACp} = \text{RMS}(IV_{TXD+} + V_{TXD-}/2 - V_{TX-CM-DC})$ $V_{TX-CM-DC} = DC_{(avg)}$ of $IV_{TX-D+} + V_{TX-D-}/2$ See Note 2
$V_{TX-CM-DC-ACTIVE-IDLE-DELTA}$	Absolute Delta of DC Common Mode Voltage During L0 and Electrical Idle	0	—	100	mV	$ V_{TX-CM-DC}(\text{during L0}) - V_{TX-CM-Idle-DC}(\text{During Electrical Idle})  \leq 100$ mV $V_{TX-CM-DC} = DC_{(avg)}$ of $IV_{TX-D+} + V_{TX-D-}/2$ [L0] $V_{TX-CM-Idle-DC} = DC_{(avg)}$ of $IV_{TX-D+} + V_{TX-D-}/2$ [Electrical Idle] See Note 2.
$V_{TX-CM-DC-LINE-DELTA}$	Absolute Delta of DC Common Mode between D+ and D-	0	—	25	mV	$ V_{TX-CM-DC-D+} - V_{TX-CM-DC-D-}  \leq 25$ mV $V_{TX-CM-DC-D+} = DC_{(avg)}$ of $IV_{TX-D+}$ $V_{TX-CM-DC-D-} = DC_{(avg)}$ of $IV_{TX-D-}$ See Note 2.
$V_{TX-IDLE-DIFFp}$	Electrical Idle differential Peak Output Voltage	0	—	20	mV	$V_{TX-IDLE-DIFFp} = IV_{TX-IDLE-D+} - V_{TX-IDLE-D-} \leq 20$ mV See Note 2.
$V_{TX-RCV-DETECT}$	The amount of voltage change allowed during Receiver Detection	—	—	600	mV	The total amount of voltage change that a transmitter can apply to sense whether a low impedance Receiver is present. See Note 6.
$V_{TX-DC-CM}$	The TX DC Common Mode Voltage	0	—	3.6	V	The allowed DC Common Mode voltage under any conditions. See Note 6.
$I_{TX-SHORT}$	TX Short Circuit Current Limit	—	—	90	mA	The total current the Transmitter can provide when shorted to its ground
$T_{TX-IDLE-MIN}$	Minimum time spent in Electrical Idle	50	—	—	UI	Minimum time a Transmitter must be in Electrical Idle Utilized by the Receiver to start looking for an Electrical Idle Exit after successfully receiving an Electrical Idle ordered set

**Table 50. Differential Receiver (RX) Input Specifications (continued)**

Symbol	Parameter	Min	Nom	Max	Units	Comments
$T_{RX-IDLE-DET-DIFF-ENTERTIME}$	Unexpected Electrical Idle Enter Detect Threshold Integration Time	—	—	10	ms	An unexpected Electrical Idle ( $V_{RX-DIFFp-p} < V_{RX-IDLE-DET-DIFFp-p}$ ) must be recognized no longer than $T_{RX-IDLE-DET-DIFF-ENTERING}$ to signal an unexpected idle condition.
$L_{TX-SKEW}$	Total Skew	—	—	20	ns	Skew across all lanes on a Link. This includes variation in the length of SKP ordered set (for example, COM and one to five Symbols) at the RX as well as any delay differences arising from the interconnect itself.

**Notes:**

- No test load is necessarily associated with this value.
- Specified at the measurement point and measured over any 250 consecutive UIs. The test load in [Figure 52](#) should be used as the RX device when taking measurements (also refer to the Receiver compliance eye diagram shown in [Figure 51](#)). If the clocks to the RX and TX are not derived from the same reference clock, the TX UI recovered from 3500 consecutive UI must be used as a reference for the eye diagram.
- A  $T_{RX-EYE} = 0.40$  UI provides for a total sum of 0.60 UI deterministic and random jitter budget for the Transmitter and interconnect collected any 250 consecutive UIs. The  $T_{RX-EYE-MEDIAN-to-MAX-JITTER}$  specification ensures a jitter distribution in which the median and the maximum deviation from the median is less than half of the total. UI jitter budget collected over any 250 consecutive TX UIs. It should be noted that the median is not the same as the mean. The jitter median describes the point in time where the number of jitter points on either side is approximately equal as opposed to the averaged time value. If the clocks to the RX and TX are not derived from the same reference clock, the TX UI recovered from 3500 consecutive UI must be used as the reference for the eye diagram.
- The Receiver input impedance shall result in a differential return loss greater than or equal to 15 dB with the D+ line biased to 300 mV and the D- line biased to -300 mV and a common mode return loss greater than or equal to 6 dB (no bias required) over a frequency range of 50 MHz to 1.25 GHz. This input impedance requirement applies to all valid input levels. The reference impedance for return loss measurements for is  $50 \Omega$  to ground for both the D+ and D- line (that is, as measured by a Vector Network Analyzer with 50 ohm probes - see [Figure 52](#)). Note: that the series capacitors  $C_{TX}$  is optional for the return loss measurement.
- Impedance during all LTSSM states. When transitioning from a Fundamental Reset to Detect (the initial state of the LTSSM) there is a 5 ms transition time before Receiver termination values must be met on all un-configured Lanes of a Port.
- The RX DC Common Mode Impedance that exists when no power is present or Fundamental Reset is asserted. This helps ensure that the Receiver Detect circuit will not falsely assume a Receiver is powered on when it is not. This term must be measured at 300 mV above the RX ground.
- It is recommended that the recovered TX UI is calculated using all edges in the 3500 consecutive UI interval with a fit algorithm using a minimization merit function. Least squares and median deviation fits have worked well with experimental and simulated data.

## 14.5 Receiver Compliance Eye Diagrams

The RX eye diagram in [Figure 51](#) is specified using the passive compliance/test measurement load (see [Figure 52](#)) in place of any real PCI Express RX component.

Note: In general, the minimum Receiver eye diagram measured with the compliance/test measurement load (see [Figure 52](#)) will be larger than the minimum Receiver eye diagram measured over a range of systems at the input Receiver of any real PCI Express component. The degraded eye diagram at the input Receiver is due to traces internal to the package as well as silicon parasitic characteristics which cause the real PCI Express component to vary in impedance from the compliance/test measurement load. The input Receiver eye diagram is implementation specific and is not specified. RX component designer should

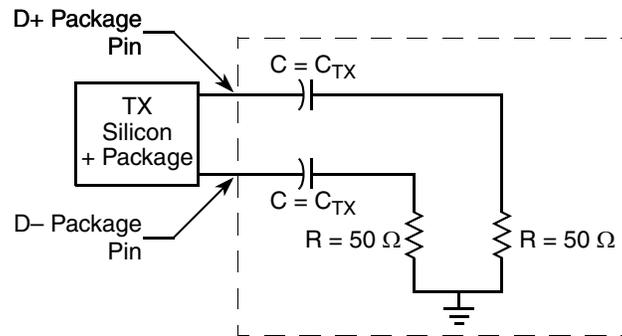


Figure 52. Compliance Test/Measurement Load

## 15 Serial RapidIO

This section describes the DC and AC electrical specifications for the RapidIO interface of the MPC8641, for the LP-Serial physical layer. The electrical specifications cover both single and multiple-lane links. Two transmitter types (short run and long run) on a single receiver are specified for each of three baud rates, 1.25, 2.50, and 3.125 GBaud.

Two transmitter specifications allow for solutions ranging from simple board-to-board interconnect to driving two connectors across a backplane. A single receiver specification is given that will accept signals from both the short run and long run transmitter specifications.

The short run transmitter specifications should be used mainly for chip-to-chip connections on either the same printed circuit board or across a single connector. This covers the case where connections are made to a mezzanine (daughter) card. The minimum swings of the short run specification reduce the overall power used by the transceivers.

The long run transmitter specifications use larger voltage swings that are capable of driving signals across backplanes. This allows a user to drive signals across two connectors and a backplane. The specifications allow a distance of at least 50 cm at all baud rates.

All unit intervals are specified with a tolerance of  $\pm 100$  ppm. The worst case frequency difference between any transmit and receive clock will be 200 ppm.

To ensure interoperability between drivers and receivers of different vendors and technologies, AC coupling at the receiver input must be used.

### 15.1 DC Requirements for Serial RapidIO $SDn\_REF\_CLK$ and $SDn\_REF\_CLK$

For more information, see [Section 13.2, “SerDes Reference Clocks.”](#)

### 15.2 AC Requirements for Serial RapidIO $SDn\_REF\_CLK$ and $SDn\_REF\_CLK$

[Table 51](#) lists AC requirements.

**Table 58. Transmitter Differential Output Eye Diagram Parameters**

Transmitter Type	V <sub>DIFFmin</sub> (mV)	V <sub>DIFFmax</sub> (mV)	A (UI)	B (UI)
1.25 GBaud short range	250	500	0.175	0.39
1.25 GBaud long range	400	800	0.175	0.39
2.5 GBaud short range	250	500	0.175	0.39
2.5 GBaud long range	400	800	0.175	0.39
3.125 GBaud short range	250	500	0.175	0.39
3.125 GBaud long range	400	800	0.175	0.39

## 15.7 Receiver Specifications

LP-Serial receiver electrical and timing specifications are stated in the text and tables of this section.

Receiver input impedance shall result in a differential return loss better than 10 dB and a common mode return loss better than 6 dB from 100 MHz to  $(0.8) \times (\text{Baud Frequency})$ . This includes contributions from on-chip circuitry, the chip package and any off-chip components related to the receiver. AC coupling components are included in this requirement. The reference impedance for return loss measurements is 100 Ohm resistive for differential return loss and 25 Ohm resistive for common mode.

**Table 59. Receiver AC Timing Specifications—1.25 GBaud**

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Differential Input Voltage	V <sub>IN</sub>	200	1600	mV p-p	Measured at receiver
Deterministic Jitter Tolerance	J <sub>D</sub>	0.37	—	UI p-p	Measured at receiver
Combined Deterministic and Random Jitter Tolerance	J <sub>DR</sub>	0.55	—	UI p-p	Measured at receiver
Total Jitter Tolerance <sup>1</sup>	J <sub>T</sub>	0.65	—	UI p-p	Measured at receiver
Multiple Input Skew	S <sub>MI</sub>	—	24	ns	Skew at the receiver input between lanes of a multilane link
Bit Error Rate	BER	—	10 <sup>-12</sup>	—	—
Unit Interval	UI	800	800	ps	+/- 100 ppm

**Note:**

- Total jitter is composed of three components, deterministic jitter, random jitter and single frequency sinusoidal jitter. The sinusoidal jitter may have any amplitude and frequency in the unshaded region of [Figure 55](#). The sinusoidal jitter component is included to ensure margin for low frequency jitter, wander, noise, crosstalk and other variable system effects.

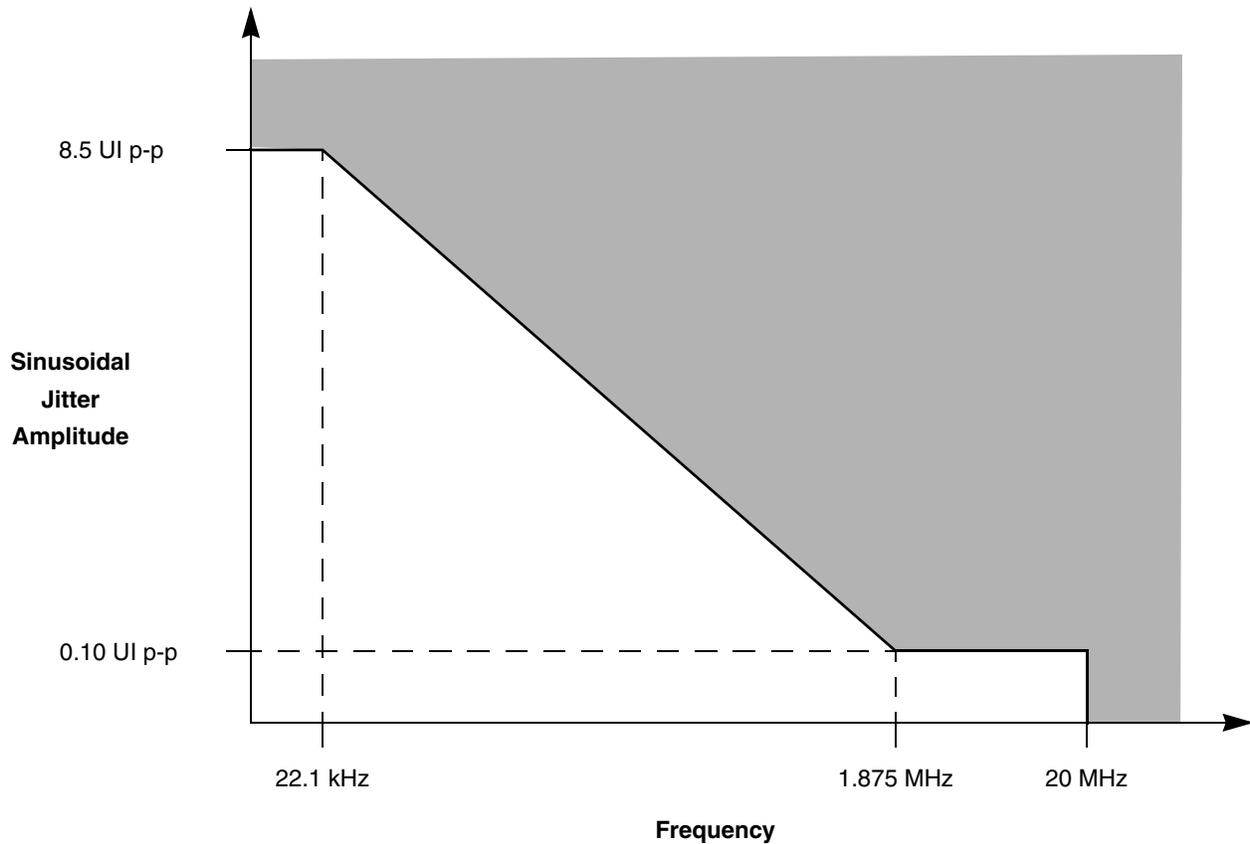


Figure 55. Single Frequency Sinusoidal Jitter Limits

## 15.8 Receiver Eye Diagrams

For each baud rate at which an LP-Serial receiver is specified to operate, the receiver shall meet the corresponding Bit Error Rate specification (Table 59, Table 60, Table 61) when the eye pattern of the receiver test signal (exclusive of sinusoidal jitter) falls entirely within the unshaded portion of the Receiver Input Compliance Mask shown in Figure 56 with the parameters specified in Table . The eye pattern of the receiver test signal is measured at the input pins of the receiving device with the device replaced with a  $100\ \Omega \pm 5\%$  differential resistive load.

Continuous Jitter Test Pattern (CJPAT) defined in Annex 48A of IEEE 802.3ae. All lanes of the LP-Serial link shall be active in both the transmit and receive directions, and opposite ends of the links shall use asynchronous clocks. Four lane implementations shall use CJPAT as defined in Annex 48A. Single lane implementations shall use the CJPAT sequence specified in Annex 48A for transmission on lane 0. The amount of data represented in the eye shall be adequate to ensure that the bit error ratio is less than  $10^{-12}$ . The eye pattern shall be measured with AC coupling and the compliance template centered at 0 Volts differential. The left and right edges of the template shall be aligned with the mean zero crossing points of the measured data eye. The load for this test shall be 100  $\Omega$  resistive  $\pm$  5% differential to 2.5 GHz.

### 15.9.2 Jitter Test Measurements

For the purpose of jitter measurement, the effects of a single-pole high pass filter with a 3 dB point at (Baud Frequency)/1667 is applied to the jitter. The data pattern for jitter measurements is the Continuous Jitter Test Pattern (CJPAT) pattern defined in Annex 48A of IEEE 802.3ae. All lanes of the LP-Serial link shall be active in both the transmit and receive directions, and opposite ends of the links shall use asynchronous clocks. Four lane implementations shall use CJPAT as defined in Annex 48A. Single lane implementations shall use the CJPAT sequence specified in Annex 48A for transmission on lane 0. Jitter shall be measured with AC coupling and at 0 Volts differential. Jitter measurement for the transmitter (or for calibration of a jitter tolerance setup) shall be performed with a test procedure resulting in a BER curve such as that described in Annex 48B of IEEE 802.3ae.

### 15.9.3 Transmit Jitter

Transmit jitter is measured at the driver output when terminated into a load of 100  $\Omega$  resistive  $\pm$  5% differential to 2.5 GHz.

### 15.9.4 Jitter Tolerance

Jitter tolerance is measured at the receiver using a jitter tolerance test signal. This signal is obtained by first producing the sum of deterministic and random jitter defined in Section 8.6 and then adjusting the signal amplitude until the data eye contacts the 6 points of the minimum eye opening of the receive template shown in Figure 8-4 and Table 8-11. Note that for this to occur, the test signal must have vertical waveform symmetry about the average value and have horizontal symmetry (including jitter) about the mean zero crossing. Eye template measurement requirements are as defined above. Random jitter is calibrated using a high pass filter with a low frequency corner at 20 MHz and a 20 dB/decade roll-off below this. The required sinusoidal jitter specified in Section 8.6 is then added to the signal and the test load is replaced by the receiver being tested.

**Table 63. MPC8641 Signal Reference by Functional Block (continued)**

Name <sup>1</sup>	Package Pin Number	Pin Type	Power Supply	Notes
TSEC3_TX_EN	AH19	O	TV <sub>DD</sub>	36
TSEC3_TX_ER	AH17	O	TV <sub>DD</sub>	—
TSEC3_TX_CLK	AH18	I	TV <sub>DD</sub>	40
TSEC3_GTX_CLK	AG19	O	TV <sub>DD</sub>	41
TSEC3_CRS	AE15	I/O	TV <sub>DD</sub>	37
TSEC3_COL	AF15	I	TV <sub>DD</sub>	—
TSEC3_RXD[0:7]	AJ17, AE16, AH16, AH14, AJ19, AH15, AG16, AE19	I	TV <sub>DD</sub>	—
TSEC3_RX_DV	AG15	I	TV <sub>DD</sub>	—
TSEC3_RX_ER	AF16	I	TV <sub>DD</sub>	—
TSEC3_RX_CLK	AJ18	I	TV <sub>DD</sub>	40
<b>eTSEC Port 4 Signals<sup>5</sup></b>				
TSEC4_TXD[0:3]	AC18, AC16, AD18, AD17	O	TV <sub>DD</sub>	6
TSEC4_TXD[4]	AD16	O	TV <sub>DD</sub>	25
TSEC4_TXD[5:7]	AB18, AB17, AB16	O	TV <sub>DD</sub>	6
TSEC4_TX_EN	AF17	O	TV <sub>DD</sub>	36
TSEC4_TX_ER	AF19	O	TV <sub>DD</sub>	—
TSEC4_TX_CLK	AF18	I	TV <sub>DD</sub>	40
TSEC4_GTX_CLK	AG17	O	TV <sub>DD</sub>	41
TSEC4_CRS	AB14	I/O	TV <sub>DD</sub>	37
TSEC4_COL	AC13	I	TV <sub>DD</sub>	—
TSEC4_RXD[0:7]	AG14, AD13, AF13, AD14, AE14, AB15, AC14, AE17	I	TV <sub>DD</sub>	—
TSEC4_RX_DV	AC15	I	TV <sub>DD</sub>	—
TSEC4_RX_ER	AF14	I	TV <sub>DD</sub>	—
TSEC4_RX_CLK	AG13	I	TV <sub>DD</sub>	40
<b>Local Bus Signals<sup>5</sup></b>				
LAD[0:31]	A30, E29, C29, D28, D29, H25, B29, A29, C28, L22, M22, A28, C27, H26, G26, B27, B26, A27, E27, G25, D26, E26, G24, F27, A26, A25, C25, H23, K22, D25, F25, H22	I/O	OV <sub>DD</sub>	6
LDP[0:3]	A24, E24, C24, B24	I/O	OV <sub>DD</sub>	6, 22
LA[27:31]	J21, K21, G22, F24, G21	O	OV <sub>DD</sub>	6, 22
$\overline{\text{LCS}}$ [0:4]	A22, C22, D23, E22, A23	O	OV <sub>DD</sub>	7
$\overline{\text{LCS}}$ [5]/DMA_DREQ[2]	B23	O	OV <sub>DD</sub>	7, 9, 10

**Table 63. MPC8641 Signal Reference by Functional Block (continued)**

Name <sup>1</sup>	Package Pin Number	Pin Type	Power Supply	Notes
$\overline{\text{LCS}}[6]/\overline{\text{DMA\_DACK}}[2]$	E23	O	OV <sub>DD</sub>	7, 10
$\overline{\text{LCS}}[7]/\overline{\text{DMA\_DDONE}}[2]$	F23	O	OV <sub>DD</sub>	7, 10
$\overline{\text{LWE}}[0:3]/$ LSDDQM[0:3]/ $\overline{\text{LBS}}[0:3]$	E21, F21, D22, E20	O	OV <sub>DD</sub>	6
LBCTL	D21	O	OV <sub>DD</sub>	—
LALE	E19	O	OV <sub>DD</sub>	—
LGPL0/LSDA10	F20	O	OV <sub>DD</sub>	25
LGPL1/ $\overline{\text{LSDWE}}$	H20	O	OV <sub>DD</sub>	25
LGPL2/ $\overline{\text{LOE}}/$ $\overline{\text{LSDRAS}}$	J20	O	OV <sub>DD</sub>	—
LGPL3/ $\overline{\text{LSDCAS}}$	K20	O	OV <sub>DD</sub>	6
LGPL4/ $\overline{\text{LGT\AA}}$ / LUPWAIT/LPBSE	L21	I/O	OV <sub>DD</sub>	42
LGPL5	J19	O	OV <sub>DD</sub>	6
LCKE	H19	O	OV <sub>DD</sub>	—
LCLK[0:2]	G19, L19, M20	O	OV <sub>DD</sub>	—
LSYNC_IN	M19	I	OV <sub>DD</sub>	—
LSYNC_OUT	D20	O	OV <sub>DD</sub>	—
<b>DMA Signals<sup>5</sup></b>				
$\overline{\text{DMA\_DREQ}}[0:1]$	E31, E32	I	OV <sub>DD</sub>	—
$\overline{\text{DMA\_DREQ}}[2]/\overline{\text{LCS}}[5]$	B23	I	OV <sub>DD</sub>	9, 10
$\overline{\text{DMA\_DREQ}}[3]/\overline{\text{IRQ}}[9]$	B30	I	OV <sub>DD</sub>	10
$\overline{\text{DMA\_DACK}}[0:1]$	D32, F30	O	OV <sub>DD</sub>	—
$\overline{\text{DMA\_DACK}}[2]/\overline{\text{LCS}}[6]$	E23	O	OV <sub>DD</sub>	10
$\overline{\text{DMA\_DACK}}[3]/\overline{\text{IRQ}}[10]$	C30	O	OV <sub>DD</sub>	9, 10
$\overline{\text{DMA\_DDONE}}[0:1]$	F31, F32	O	OV <sub>DD</sub>	—
$\overline{\text{DMA\_DDONE}}[2]/\overline{\text{LCS}}[7]$	F23	O	OV <sub>DD</sub>	10
$\overline{\text{DMA\_DDONE}}[3]/\overline{\text{IRQ}}[11]$	D30	O	OV <sub>DD</sub>	9, 10
<b>Programmable Interrupt Controller Signals<sup>5</sup></b>				
$\overline{\text{MCP\_0}}$	F17	I	OV <sub>DD</sub>	—
$\overline{\text{MCP\_1}}$	H17	I	OV <sub>DD</sub>	12, S4
IRQ[0:8]	G28, G29, H27, J23, M23, J27, F28, J24, L23	I	OV <sub>DD</sub>	—

Another useful equation is:

$$V_H - V_L = n \frac{KT}{q} \left[ \ln \frac{I_H}{I_L} \right]$$

Where:

$I_{fw}$  = Forward current

$I_s$  = Saturation current

$V_d$  = Voltage at diode

$V_f$  = Voltage forward biased

$V_H$  = Diode voltage while  $I_H$  is flowing

$V_L$  = Diode voltage while  $I_L$  is flowing

$I_H$  = Larger diode bias current

$I_L$  = Smaller diode bias current

$q$  = Charge of electron ( $1.6 \times 10^{-19}$  C)

$n$  = Ideality factor (normally 1.0)

$K$  = Boltzman's constant ( $1.38 \times 10^{-23}$  Joules/K)

$T$  = Temperature (Kelvins)

The ratio of  $I_H$  to  $I_L$  is usually selected to be 10:1. The above simplifies to the following:

$$V_H - V_L = 1.986 \times 10^{-4} \times nT$$

Solving for  $T$ , the equation becomes:

$$nT = \frac{V_H - V_L}{1.986 \times 10^{-4}}$$

## 20.8 Configuration Pin Muxing

The MPC8641 provides the user with power-on configuration options which can be set through the use of external pull-up or pull-down resistors of 4.7 k $\Omega$  on certain output pins (see customer visible configuration pins). These pins are generally used as output only pins in normal operation.

While  $\overline{\text{HRESET}}$  is asserted however, these pins are treated as inputs. The value presented on these pins while  $\overline{\text{HRESET}}$  is asserted, is latched when  $\overline{\text{HRESET}}$  deasserts, at which time the input receiver is disabled and the I/O circuit takes on its normal function. Most of these sampled configuration pins are equipped with an on-chip gated resistor of approximately 20 k $\Omega$ . This value should permit the 4.7-k $\Omega$  resistor to pull the configuration pin to a valid logic low level. The pull-up resistor is enabled only during  $\overline{\text{HRESET}}$  (and for platform /system clocks after  $\overline{\text{HRESET}}$  deassertion to ensure capture of the reset value). When the input receiver is disabled the pull-up is also, thus allowing functional operation of the pin as an output with minimal signal quality or delay disruption. The default value for all configuration bits treated this way has been encoded such that a high voltage level puts the device into the default state and external resistors are needed only when non-default settings are required by the user.

Careful board layout with stubless connections to these pull-down resistors coupled with the large value of the pull-down resistor should minimize the disruption of signal quality or speed for output pins thus configured.

The platform PLL ratio and e600 PLL ratio configuration pins are not equipped with these default pull-up devices.

## 20.9 JTAG Configuration Signals

Correct operation of the JTAG interface requires configuration of a group of system control pins as demonstrated in [Figure 68](#). Care must be taken to ensure that these pins are maintained at a valid deasserted state under normal operating conditions as most have asynchronous behavior and spurious assertion will give unpredictable results.

Boundary-scan testing is enabled through the JTAG interface signals. The  $\overline{\text{TRST}}$  signal is optional in the IEEE 1149.1 specification, but is provided on all processors that implement the Power Architecture technology. The device requires  $\overline{\text{TRST}}$  to be asserted during reset conditions to ensure the JTAG boundary logic does not interfere with normal chip operation. While it is possible to force the TAP controller to the reset state using only the TCK and TMS signals, more reliable power-on reset performance will be obtained if the  $\overline{\text{TRST}}$  signal is asserted during power-on reset. Because the JTAG interface is also used for accessing the common on-chip processor (COP) function, simply tying  $\overline{\text{TRST}}$  to  $\overline{\text{HRESET}}$  is not practical.

The COP function of these processors allows a remote computer system (typically a PC with dedicated hardware and debugging software) to access and control the internal operations of the processor. The COP port connects primarily through the JTAG interface of the processor, with some additional status monitoring signals. The COP port requires the ability to independently assert  $\overline{\text{HRESET}}$  or  $\overline{\text{TRST}}$  in order to fully control the processor. If the target system has independent reset sources, such as voltage monitors, watchdog timers, power supply failures, or push-button switches, then the COP reset signals must be merged into these signals with logic.

The arrangement shown in [Figure 67](#) allows the COP port to independently assert  $\overline{\text{HRESET}}$  or  $\overline{\text{TRST}}$ , while ensuring that the target can drive  $\overline{\text{HRESET}}$  as well.

The COP interface has a standard header, shown in [Figure 67](#), for connection to the target system, and is based on the 0.025" square-post, 0.100" centered header assembly (often called a Berg header). The connector typically has pin 14 removed as a connector key.

The COP header adds many benefits such as breakpoints, watchpoints, register and memory examination/modification, and other standard debugger features. An inexpensive option can be to leave the COP header unpopulated until needed.

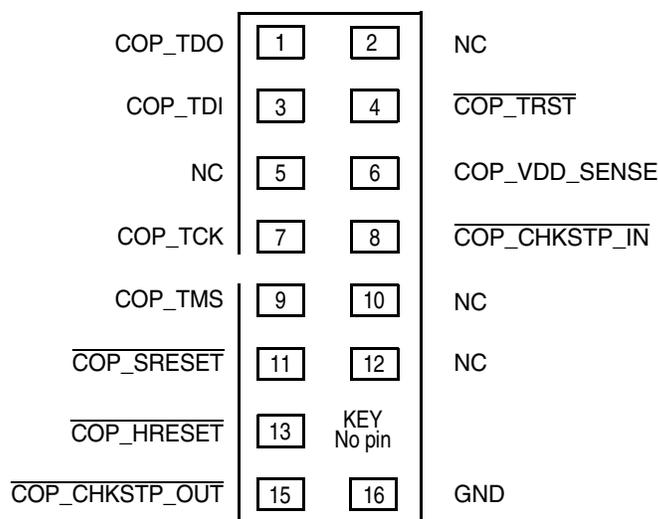
There is no standardized way to number the COP header shown in [Figure 67](#); consequently, many different pin numbers have been observed from emulator vendors. Some are numbered top-to-bottom then left-to-right, while others use left-to-right then top-to-bottom, while still others number the pins counter clockwise from pin 1 (as with an IC). Regardless of the numbering, the signal placement recommended in [Figure 67](#) is common to all known emulators.

For a multi-processor non-daisy chain configuration, [Figure 68](#), can be duplicated for each processor. The recommended daisy chain configuration is shown in [Figure 69](#). Please consult with your tool vendor to determine which configuration is supported by their emulator.

## 20.9.1 Termination of Unused Signals

If the JTAG interface and COP header will not be used, Freescale recommends the following connections:

- $\overline{\text{TRST}}$  should be tied to  $\overline{\text{HRESET}}$  through a 0 k $\Omega$  isolation resistor so that it is asserted when the system reset signal ( $\overline{\text{HRESET}}$ ) is asserted, ensuring that the JTAG scan chain is initialized during the power-on reset flow. Freescale recommends that the COP header be designed into the system as shown in [Figure 68](#). If this is not possible, the isolation resistor will allow future access to  $\overline{\text{TRST}}$  in case a JTAG interface may need to be wired onto the system in future debug situations.
- Tie TCK to  $\text{OV}_{\text{DD}}$  through a 10 k $\Omega$  resistor. This will prevent TCK from changing state and reading incorrect data into the device.
- No connection is required for TDI, TMS, or TDO.



**Figure 67. COP Connector Physical Pinout**